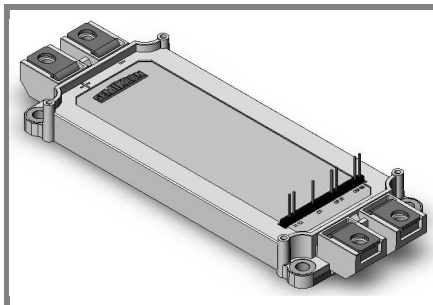


# SEMiX 604GB126HD



**SEMiX™ 4**

## Trench IGBT Modules

### SEMiX 604GB126HD

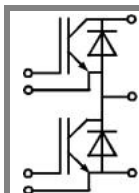
#### Target Data

#### Features

- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability

#### Typical Applications

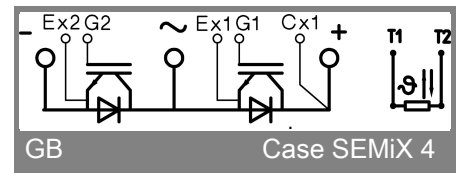
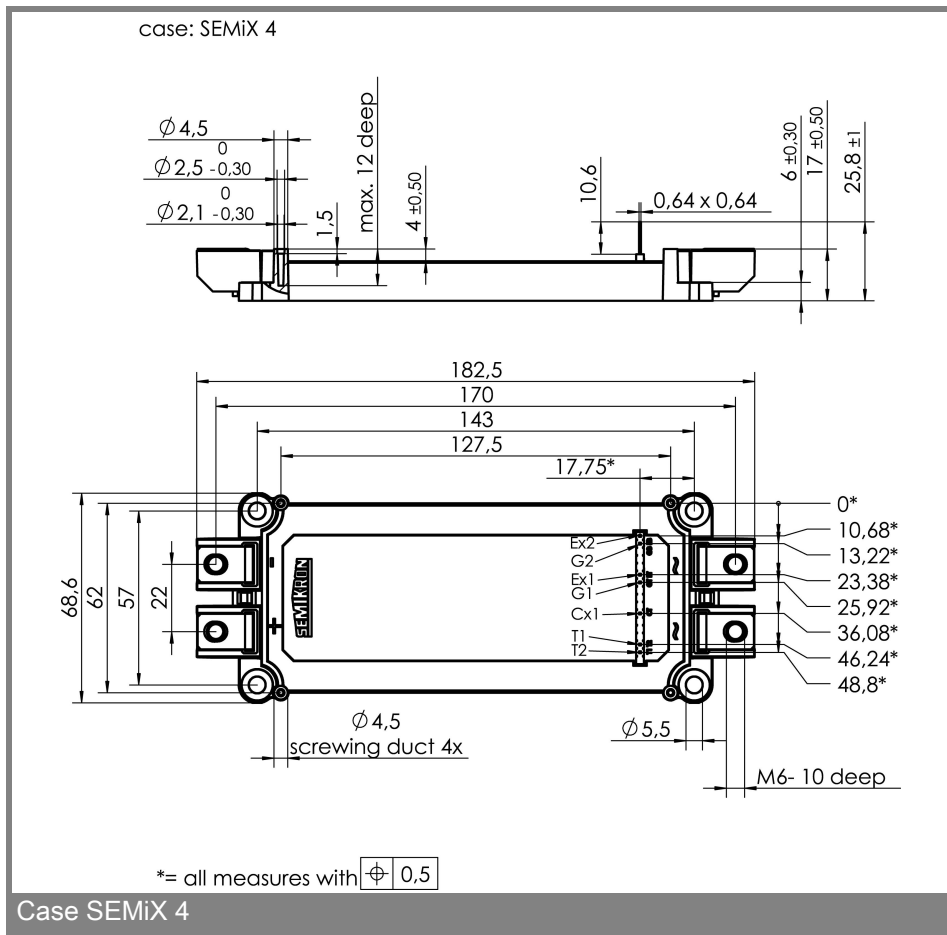
- AC inverter drives
- UPS
- Electronic welders



GB

Absolute Maximum Ratings		$T_c = 25\text{ °C}$ , unless otherwise specified	
Symbol	Conditions	Values	Units
<b>IGBT</b>			
$V_{CES}$		1200	V
$I_C$	$T_c = 25\text{ (80) °C}$	620 (440)	A
$I_{CRM}$	$T_c = 25\text{ (80) °C}$ , $t_p = 1\text{ ms}$	1240 (880)	A
$V_{GES}$		$\pm 20$	V
$T_{vj}$ ( $T_{stg}$ )	$T_{OPERATION} \leq T_{stg}$	- 40 ... + 150 (125)	°C
$V_{isol}$	AC, 1 min.	4000	V
<b>Inverse diode</b>			
$I_F = -I_C$	$T_c = 25\text{ (80) °C}$	500 (340)	A
$I_{FRM}$	$T_c = 25\text{ (80) °C}$ , $t_p = 1\text{ ms}$	1240 (880)	A
$I_{FSM}$	$t_p = 10\text{ ms}$ ; sin.; $T_j = 25\text{ °C}$		A

Characteristics		$T_c = 25\text{ °C}$ , unless otherwise specified			
Symbol	Conditions	min.	typ.	max.	Units
<b>IGBT</b>					
$V_{GE(th)}$	$V_{GE} = V_{CE}$ , $I_C = 16\text{ mA}$	5	5,8	6,5	V
$I_{CES}$	$V_{GE} = 0$ , $V_{CE} = V_{CES}$ , $T_j = 25\text{ (125) °C}$			3	mA
$V_{CE(TO)}$	$T_j = 25\text{ (125) °C}$		1 (0,9)	1,2 (1,1)	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ , $T_j = 25\text{ (125) °C}$		1,75 (2,75)	2,4 (3,4)	mΩ
$V_{CE(sat)}$	$I_C = 400\text{ A}$ , $V_{GE} = 15\text{ V}$ , $T_j = 25\text{ (125) °C}$ , chip level		1,7 (2)	2,15 (2,45)	V
$C_{ies}$	under following conditions		28,8		nF
$C_{oes}$	$V_{GE} = 0$ , $V_{CE} = 25\text{ V}$ , $f = 1\text{ MHz}$		1,5		nF
$C_{res}$			1,3		nF
$L_{CE}$			22		nH
$R_{CC'+EE'}$	resistance, terminal-chip, $T_c = 25\text{ (125) °C}$				mΩ
$t_{d(on)}/t_r$	$V_{CC} = 600\text{ V}$ , $I_C = 400\text{ A}$				ns
$t_{d(off)}/t_f$	$V_{GE} = \pm 15\text{ V}$				ns
$E_{on} (E_{off})$	$R_{Gon} = R_{Goff} = \Omega$ , $T_j = 125\text{ °C}$		36 (64)		mJ
<b>Inverse diode</b>					
$V_F = V_{EC}$	$I_F = 400\text{ A}$ ; $V_{GE} = 0\text{ V}$ ; $T_j = 25\text{ (125) °C}$ , chip level		1,6 (1,6)	1,8 (1,8)	V
$V_{(TO)}$	$T_j = 25\text{ (125) °C}$		1 (0,8)	1,1 (0,9)	V
$r_T$	$T_j = 25\text{ (125) °C}$		1,5 (2)	1,8 (2,3)	mΩ
$I_{RRM}$	$I_F = 400\text{ A}$ ; $T_j = 25\text{ (125) °C}$				A
$Q_{rr}$	$di/dt = A/\mu s$				μC
$E_{rr}$	$V_{GE} = V$				mJ
<b>Thermal characteristics</b>					
$R_{th(j-c)}$	per IGBT			0,06	K/W
$R_{th(j-c)D}$	per Inverse Diode			0,13	K/W
$R_{th(j-c)FD}$	per FWD				K/W
$R_{th(c-s)}$	per module		0,03		K/W
<b>Temperature sensor</b>					
$R_{25}$	$T_c = 25\text{ °C}$		5 ±5%		kΩ
$B_{25/85}$	$R_2 = R_1 \exp[B(1/T_2 - 1/T_1)]$ ; $T[K]; B$		3420		K
<b>Mechanical data</b>					
$M_s/M_t$	to heatsink (M5) / for terminals (M6)	3/2,5		5 / 5	Nm
w			390		g



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.